

ATTY. DOCKET NO.

4105-1

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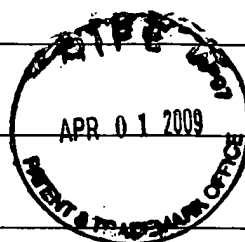
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(Use several sheets if necessary)

[illegible]

FOREIGN PATENT DOCUMENTS

							TRANSLATION	
DOCUMENT			DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
		1 351 939	05/1974	GB				
		55 139643	10/1980	JP			ABSTRACT	
		59-22250	02/1984	JP			ABSTRACT	
		63-001175	01/1988	JP			ABSTRACT	
		06-267122	09/1994	JP			ABSTRACT	
		08-212604	08/1996	JP				
		09-097457	04/1997	JP			ABSTRACT	
		09-153235	06/1997	JP			ABSTRACT	
		09-222430	08/1997	JP			ABSTRACT	
		10-334525	12/1998	JP			ABSTRACT	
		11-045467	02/1999	JP			ABSTRACT	
		11-176033	07/1999	JP			ABSTRACT	
		1 333 436	08/2003	EP				
		1 369 864	12/2003	EP				
		1 381 042	01/2004	EP				
		1 398 779	03/2004	EP				
		1 398 780	03/2004	EP				

***Examiner**

Date Considered

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ATTY. DOCKET NO.

4105-74

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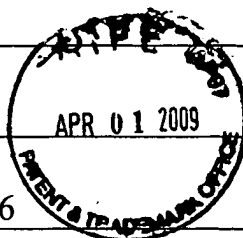
March 22, 2006

SERIAL NO.

10/568,943

TC/A.U.

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(Use several sheets if necessary)

[illegible]

							TRANSLATION	
DOCUMENT			DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
		1 351 939	05/1974	GB				
		55 139643	10/1980	JP			ABSTRACT	
		59-22250	02/1984	JP			ABSTRACT	
		63-001175	01/1988	JP			ABSTRACT	
		06-267122	09/1994	JP			ABSTRACT	
		08-212604	08/1996	JP				
		09-097457	04/1997	JP			ABSTRACT	
		09-153235	06/1997	JP			ABSTRACT	
		09-222430	08/1997	JP			ABSTRACT	
		10-334525	12/1998	JP			ABSTRACT	
		11-045467	02/1999	JP			ABSTRACT	
		11-176033	07/1999	JP			ABSTRACT	
		1 333 436	08/2003	EP				
		1 369 864	12/2003	EP				
		1 381 042	01/2004	EP				
		1 398 779	03/2004	EP				
		1 398 780	03/2004	EP				

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**INFORMATION DISCLOSURE
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OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

	Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2. (Abstract)
	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584. (Abstract)
	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO ₃ /single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217. (Abstract)
	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.
	Cho et al, "Tbit/inch ² ferroelectric data storage based on scanning nonlinear dielectric microscopy", Applied Physics Letters, Vol. 81, No. 23, December 2, 2002, pages 4401-4403.
	Odagawa et al, "Measuring ferroelectric polarization component parallel to the surface by scanning nonlinear dielectric microscopy", Applied Physics Letters, vol. 80, No. 12, Mar. 25, 2002.
	Matsuura et al, "Fundamental Study on Nano Domain Engineering Using Scanning Nonlinear Dielectric Microscopy", Jpn. J. Appl. Phys. vol. 40 (2001) pp. 4354-4356, Part 1, No. 6B Jun. 2001.

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